

# HAF2026RJ

## Silicon N Channel Power MOS FET Power Switching

REJ03G1255-0200

Rev.2.00

Jun 02, 2006

### Description

This FET has the over temperature shut-down capability sensing to the junction temperature. This FET has the built-in over temperature shut-down circuit in the gate area. And this circuit operation to shut-down the gate voltage in case of high junction temperature like applying over power consumption, over current etc..

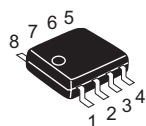
### Features

- Logic level operation (5 to 6 V Gate drive)
- Built-in the over temperature shut-down circuit
- High endurance capability against to the shut-down circuit
- Latch type shut down operation (need 0 voltage recovery)
- Built-in the current limitation circuit

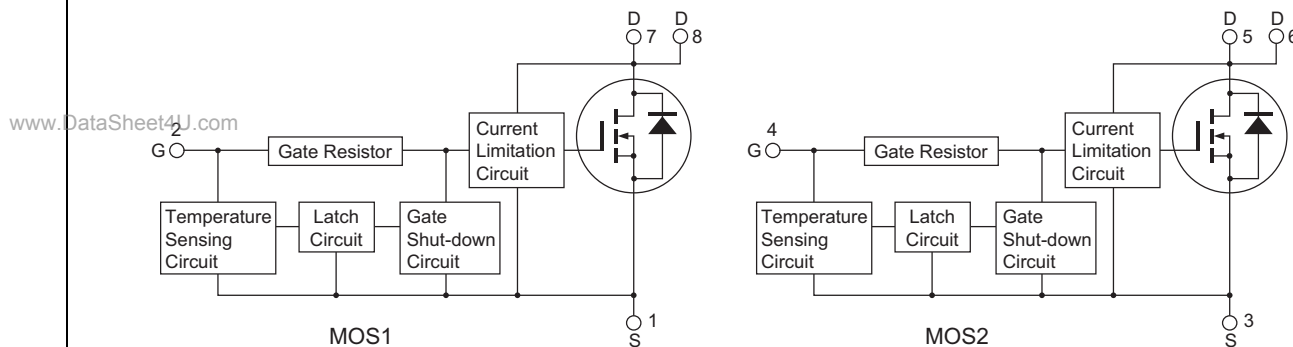
### Outline

RENESAS Package code: PRSP0008DD-D

(Package name: SOP-8 (FP-8DAV))



1, 3 Source  
2, 4 Gate  
5, 6, 7, 8 Drain



## Absolute Maximum Ratings

(Ta = 25°C)

Item	Symbol	Ratings	Unit
Drain to source voltage	V <sub>DSS</sub>	60	V
Gate to source voltage	V <sub>GSS</sub>	16	V
Gate to source voltage	V <sub>GSS</sub>	-2.5	V
Drain current	I <sub>D</sub>	0.6	A
Body-drain diode reverse drain current	I <sub>DR</sub>	1	A
Avalanche current	I <sub>AP</sub> <sup>Note3</sup>	0.6	A
Avalanche energy	E <sub>AR</sub> <sup>Note3</sup>	1.54	mJ
Cannel dissipation	P <sub>ch</sub> <sup>Note1</sup>	1	W
Cannel dissipation	P <sub>ch</sub> <sup>Note2</sup>	1.5	W
Cannel temperature	T <sub>ch</sub>	150	°C
Storage temperature	T <sub>stg</sub>	-55 to +150	°C

Notes: 1. 1 Drive operation: When using the glass epoxy board (FR4 40 x 40 x 1.6 mm), PW ≤ 10s  
 2. 2 Drive operation: When using the glass epoxy board (FR4 40 x 40 x 1.6 mm), PW ≤ 10s  
 3. T<sub>c</sub> = 25°C, R<sub>g</sub> ≥ 50 Ω

## Typical Operation Characteristics

(Ta=25°C)

Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Input voltage	V <sub>IH</sub>	3.5	—	—	V	
	V <sub>IL</sub>	—	—	1.2	V	
Input current (Gate non shut down)	I <sub>IH1</sub>	—	—	100	μA	V <sub>i</sub> = 8 V, V <sub>DS</sub> = 0
	I <sub>IH2</sub>	—	—	50	μA	V <sub>i</sub> = 3.5 V, V <sub>DS</sub> = 0
	I <sub>IL</sub>	—	—	1	μA	V <sub>i</sub> = 1.2 V, V <sub>DS</sub> = 0
Input current (Gate shut down)	I <sub>IH(sd)1</sub>	—	0.53	—	mA	V <sub>i</sub> = 8 V, V <sub>DS</sub> = 0
	I <sub>IH(sd)2</sub>	—	0.23	—	mA	V <sub>i</sub> = 3.5 V, V <sub>DS</sub> = 0
Shut down temperature	T <sub>sd</sub>	—	175	—	°C	Cannel temperature
Gate operation voltage	V <sub>op</sub>	3.5	—	12	V	
Drain current (Current limitation)	I <sub>D limit</sub>	0.6	—	1.0	A	V <sub>i</sub> = 5 V, V <sub>DS</sub> = 3 V

## Electrical Characteristics

(Ta = 25°C)

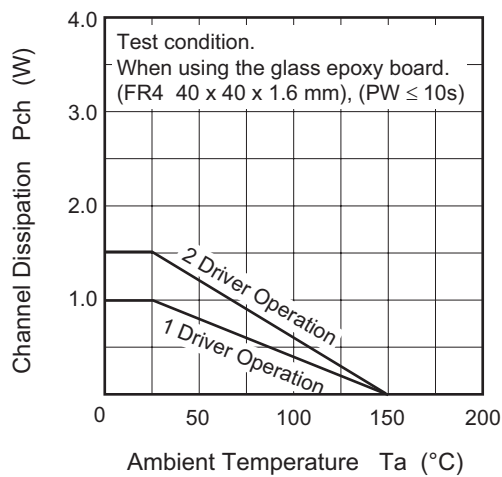
Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Drain current	$I_{D1}$	0.25	—	—	A	$V_{GS} = 3.5 \text{ V}, V_{DS} = 2 \text{ V}$
	$I_{D2}$	—	—	10	mA	$V_{GS} = 1.2 \text{ V}, V_{DS} = 2 \text{ V}$
	$I_{D3}$	0.6	—	1.0	A	$V_{GS} = 5 \text{ V}, V_{DS} = 3 \text{ V}$
Drain to source breakdown voltage	$V_{(BR)DSS}$	60	—	—	V	$I_D = 10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS}$	16	—	—	V	$I_G = 800 \mu\text{A}, V_{DS} = 0$
	$V_{(BR)GSS}$	-2.5	—	—	V	$I_G = -100 \mu\text{A}, V_{DS} = 0$
Gate to source leak current	$I_{GSS1}$	—	—	100	$\mu\text{A}$	$V_{GS} = 8 \text{ V}, V_{DS} = 0$
	$I_{GSS2}$	—	—	50	$\mu\text{A}$	$V_{GS} = 3.5 \text{ V}, V_{DS} = 0$
	$I_{GSS3}$	—	—	1	$\mu\text{A}$	$V_{GS} = 1.2 \text{ V}, V_{DS} = 0$
	$I_{GSS4}$	—	—	-100	$\mu\text{A}$	$V_{GS} = -2.4 \text{ V}, V_{DS} = 0$
Input current (shut down)	$I_{GS(OP)1}$	—	0.53	—	mA	$V_{GS} = 8 \text{ V}, V_{DS} = 0$
	$I_{GS(OP)2}$	—	0.23	—	mA	$V_{GS} = 3.5 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	$I_{DSS1}$	—	—	10	$\mu\text{A}$	$V_{DS} = 60 \text{ V}, V_{GS} = 0$
	$I_{DSS2}$	—	—	10	$\mu\text{A}$	$V_{DS} = 48 \text{ V}, V_{GS} = 0, T_a = 125^\circ\text{C}$
Gate to source cut off voltage	$V_{GS(off)}$	1.4	—	2.5	V	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$
Forward transfer admittance	$ y_{fs} $	0.26	1.3	—	S	$I_D = 0.5 \text{ A}, V_{DS} = 10 \text{ V}$ <sup>Note4</sup>
Static drain to source on state resistance	$R_{DS(on)}$	—	200	300	$\text{m}\Omega$	$I_D = 0.5 \text{ A}, V_{GS} = 5 \text{ V}$ <sup>Note4</sup>
	$R_{DS(on)}$	—	150	210	$\text{m}\Omega$	$I_D = 0.5 \text{ A}, V_{GS} = 10 \text{ V}$ <sup>Note4</sup>
Output capacitance	$C_{oss}$	—	140	—	pF	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1\text{MHz}$
Turn-on delay time	$t_{d(on)}$	—	2.9	—	$\mu\text{s}$	$V_{GS} = 5 \text{ V}, I_D = 0.5 \text{ A}, R_L = 60 \Omega$
Rise time	$t_r$	—	11	—	$\mu\text{s}$	
Turn off delay time	$t_{d(off)}$	—	0.9	—	$\mu\text{s}$	
Fall time	$t_f$	—	1	—	$\mu\text{s}$	
Body-drain diode forward voltage	$V_{DF}$	—	0.9	—	V	$I_F = 1 \text{ A}, V_{GS} = 0$
Body-drain diode reverse recovery time	$t_{rr}$	—	61	—	ns	$I_F = 1 \text{ A}, V_{GS} = 0, di_F/dt = 50 \text{ A}/\mu\text{s}$
Over load shut down operation time <sup>note5</sup>	$t_{os1}$	—	85	—	ms	$V_{GS} = 5 \text{ V}, V_{DD} = 16 \text{ V}$
	$t_{os2}$	—	30	—	ms	$V_{GS} = 5 \text{ V}, V_{DD} = 24 \text{ V}$

Notes: 4. Pulse test

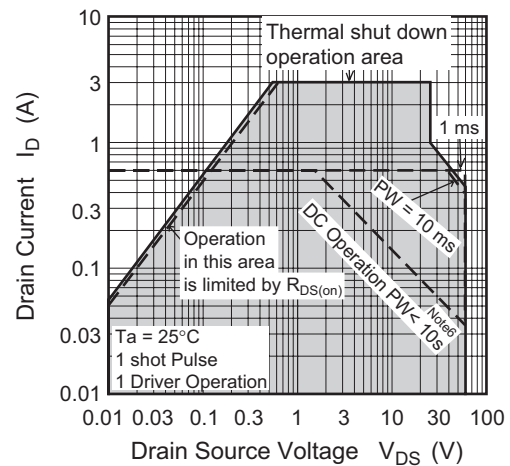
5. Including the junction temperature rise of the over loded condition.

## Main Characteristics

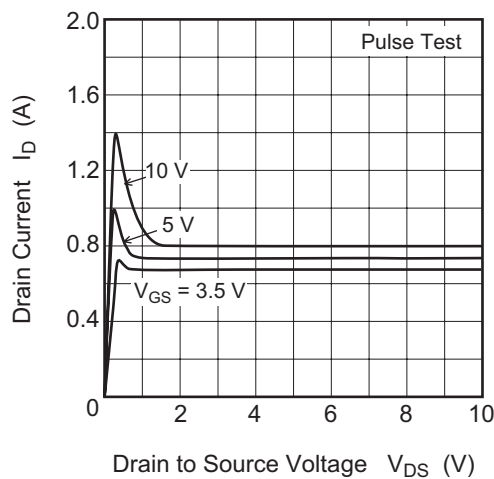
Power vs. Temperature Derating



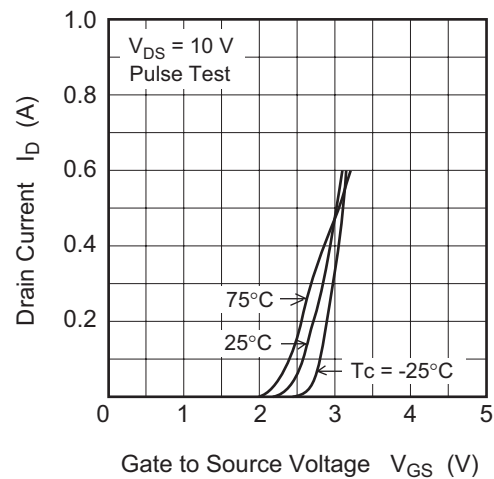
Maximum Safe Operation Area



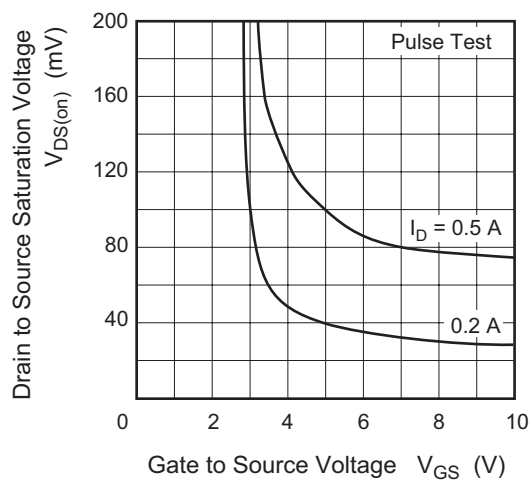
Typical Output Characteristics



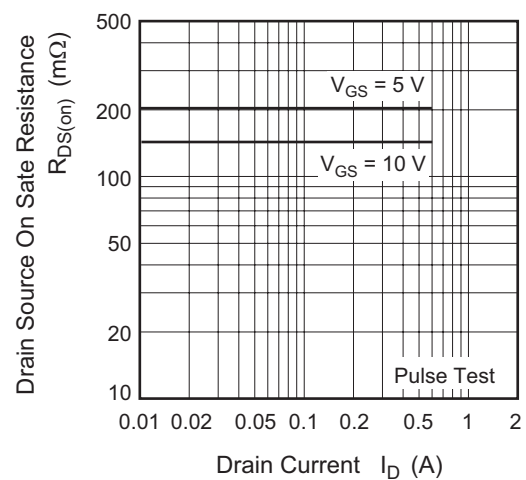
Typical Transfer Characteristics



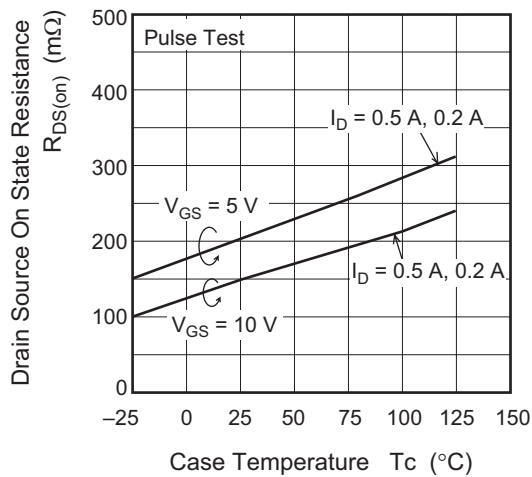
Drain to Saturation Voltage vs. Gate to Source Voltage



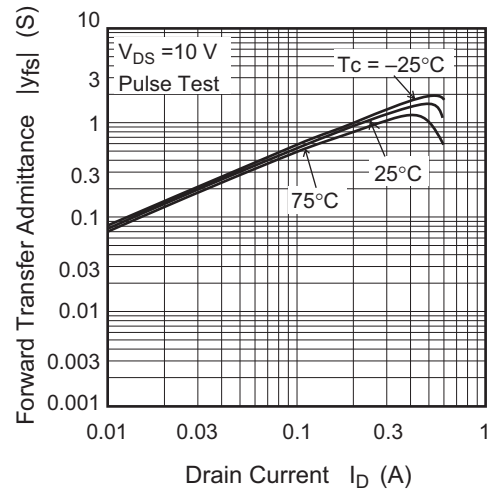
Static Drain to Source State Resistance vs. Drain Current



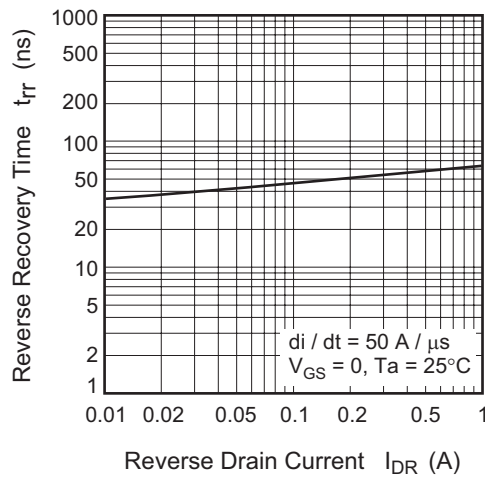
Drain to Source On State Resistance  
vs. Temperature



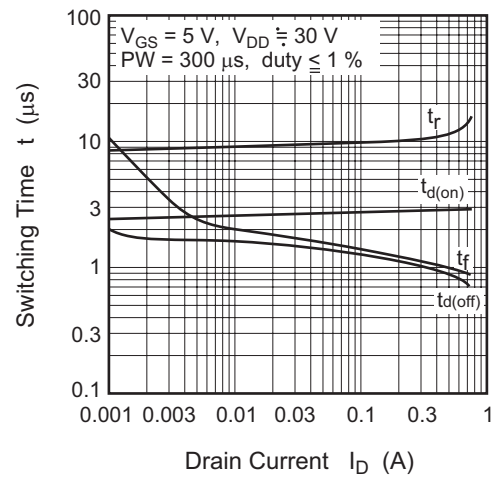
Forward Transfer Admittance vs.  
Drain Current



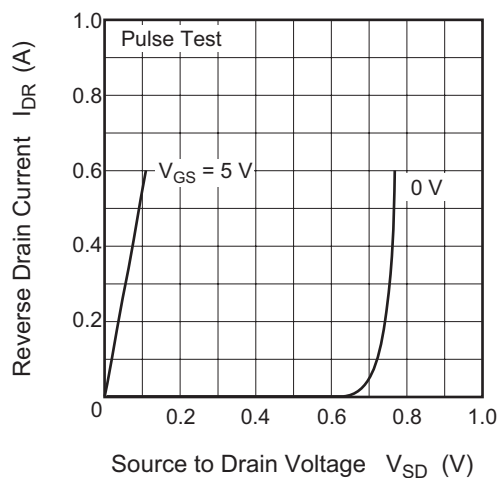
Body to Drain Diode Reverse  
Recovery Time



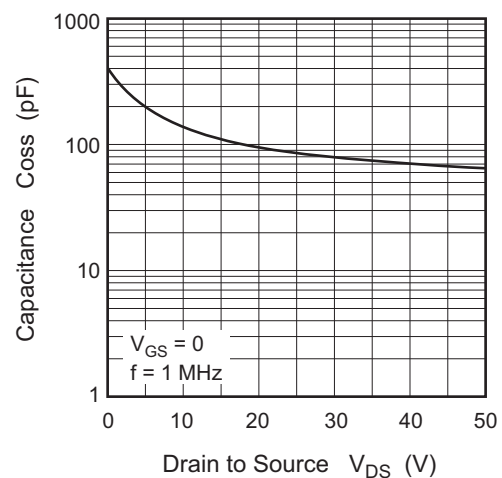
Switching Characteristics

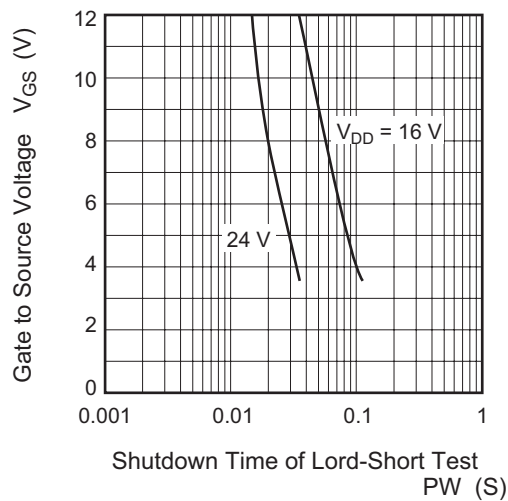
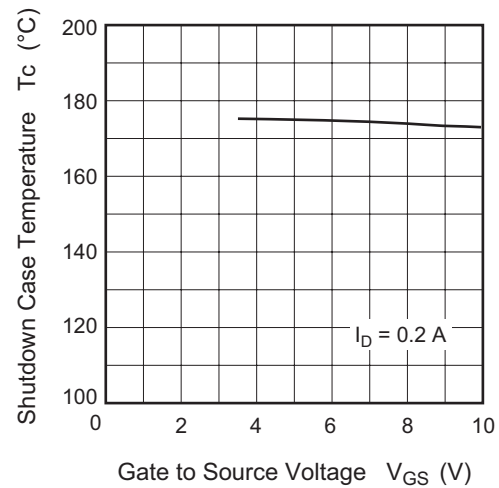
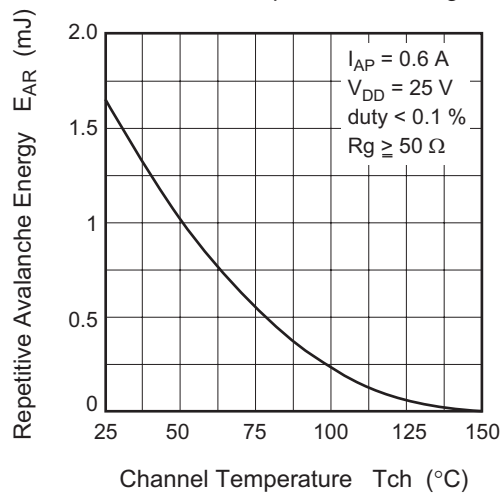


Reverse Drain Current vs.  
Source to Drain Voltage



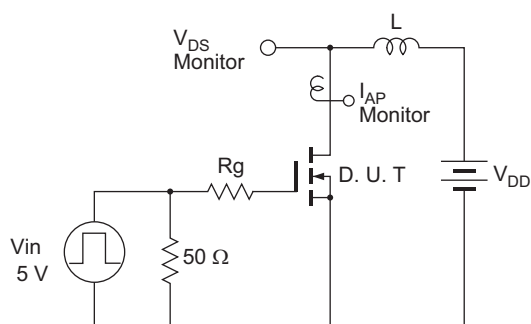
Typical capacitance vs.  
Drain to Source Voltage



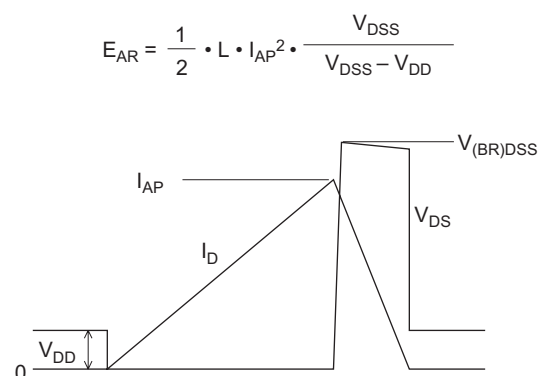
Gate to Source Voltage vs.  
Shutdown Time of Load-Short TestShutdown Case Temperature vs.  
Gate to Source VoltageAvalanche Energy vs.  
Channel Temperature Derating

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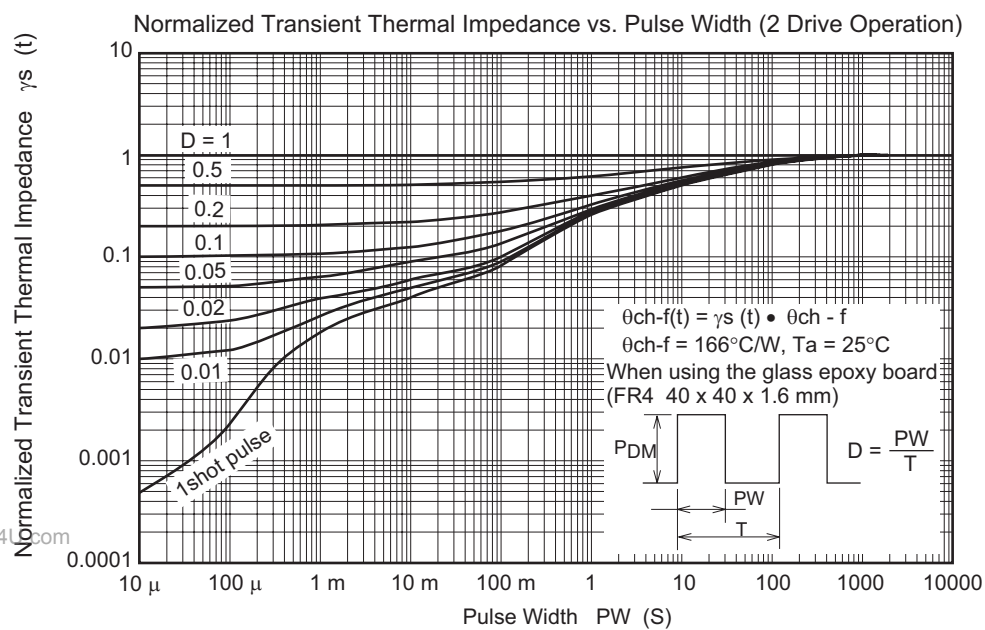
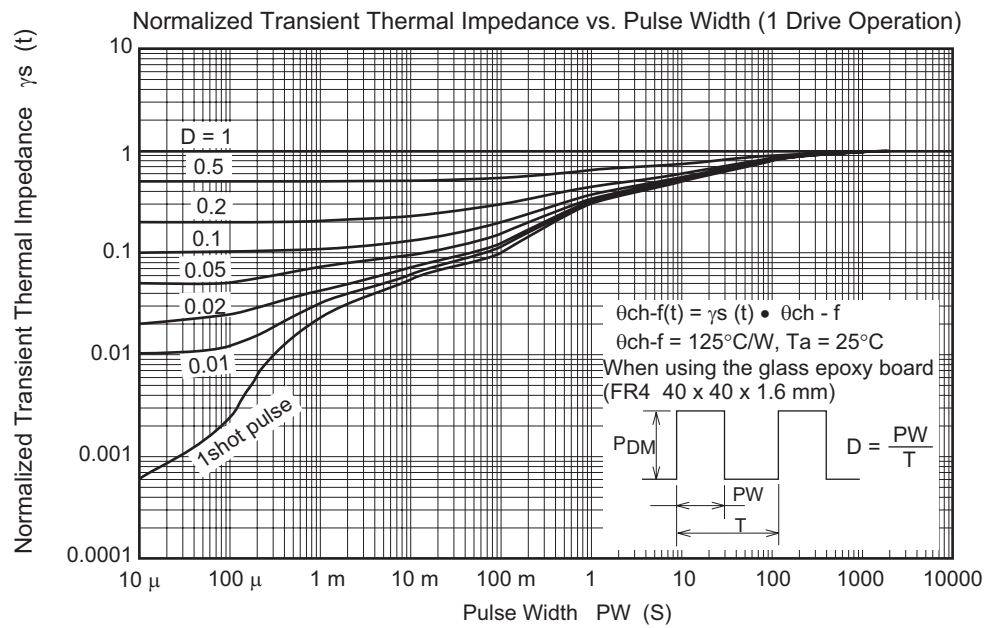
Avalanche Test Circuit



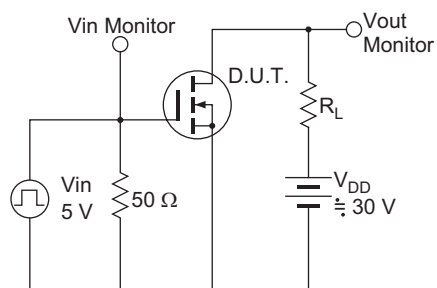
Avalanche Waveform



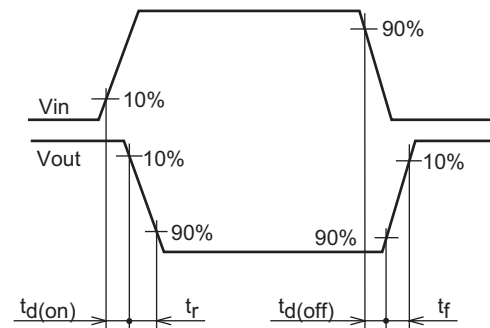
$$E_{AR} = \frac{1}{2} \cdot L \cdot I_{AP}^2 \cdot \frac{V_{DSS}}{V_{DSS} - V_{DD}}$$



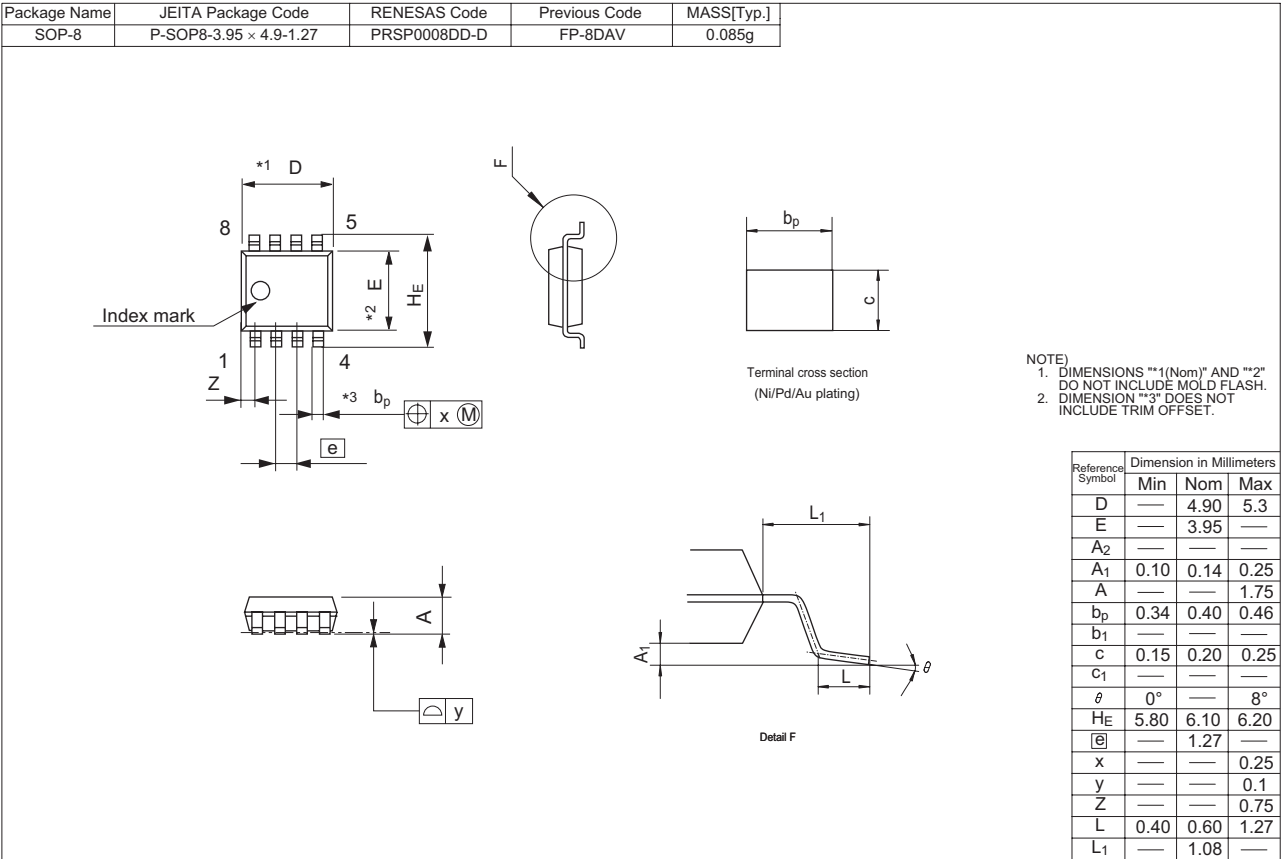
Switching Time Test Circuit



Switching Time Waveform



Package Dimensions



Ordering Information

Part Name	Quantity	Shipping Container
HAF2026RJ-EL-E	2500 pcs	Taping

Note: For some grades, production may be terminated.  
Please contact the Renesas sales office to check the state of production before ordering the product.



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